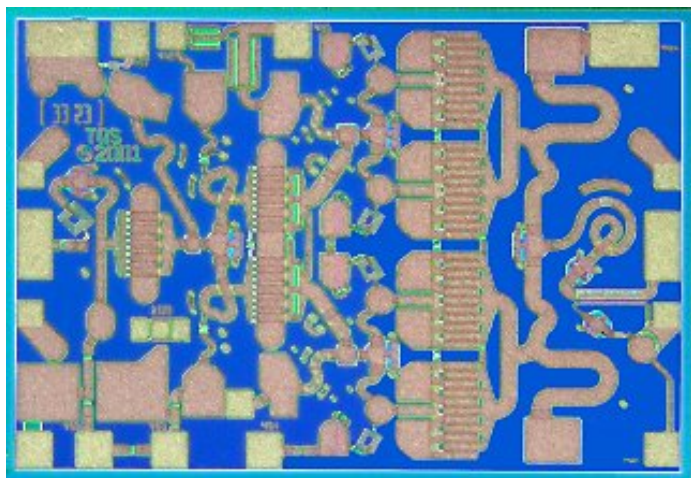


# Ku Band, 2 Watt Power Amplifier

# TGA2510

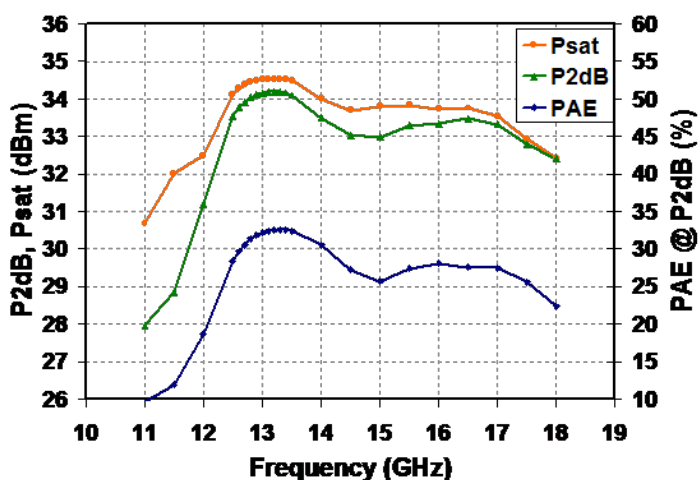
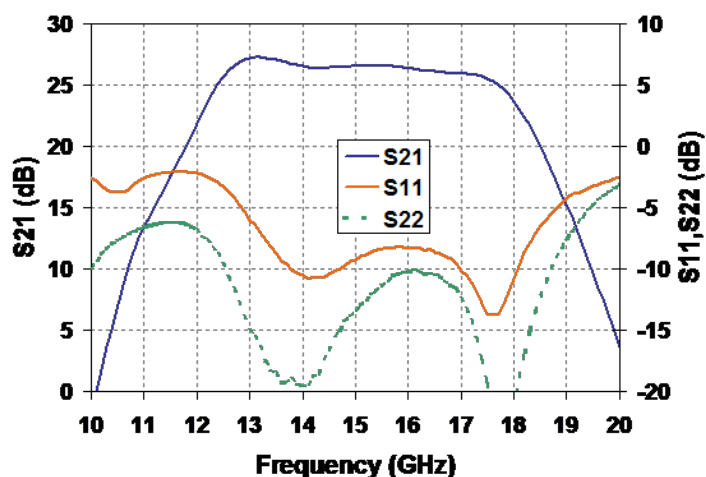


## Key Features and Performance

- 34 dBm Midband Psat
- 26 dB Nominal Gain
- 7 dB Typical Input Return Loss
- 12 dB Typical Output Return Loss
- 12.5 - 17 GHz Frequency Range
- Directional Power Detector with Reference
- 0.25μm pHEMT 3MI Technology
- Bias Conditions: 7.5V, 650mA
- Chip Dimensions:  
2.02 x 1.38 x 0.10 mm  
(0.080 x 0.054 x 0.004 inches)

## Preliminary Measured Performance

Bias Conditions: Vd=7.5V Id=650mA



Note: Datasheet is subject to change without notice.

## Primary Applications

- VSAT
- Point to Point

**TABLE I**  
**ABSOLUTE MAXIMUM RATINGS**

| Symbol    | Parameter                            | Value         | Notes               |
|-----------|--------------------------------------|---------------|---------------------|
| $V_D$     | Drain Voltage                        | 8 V           | <u>1/</u> <u>2/</u> |
| $V_G$     | Gate Voltage Range                   | -5V to 0V     | <u>1/</u>           |
| $I_D$     | Drain Supply Current                 | 1300 mA       | <u>1/</u> <u>2/</u> |
| $ I_G $   | Gate Supply Current                  | 18 mA         | <u>1/</u>           |
| $P_{IN}$  | Input Continuous Wave Power          | 24 dBm        | <u>1/</u> <u>2/</u> |
| $P_D$     | Power Dissipation                    | 10.4 W        | <u>1/</u> <u>2/</u> |
| $T_{CH}$  | Operating Channel Temperature        | 200 °C        | <u>3/</u>           |
| $T_M$     | Mounting Temperature<br>(30 Seconds) | 320 °C        |                     |
| $T_{STG}$ | Storage Temperature                  | -65 to 150 °C |                     |

- 1/ These ratings represent the maximum operable values for this device
- 2/ Combinations of supply voltage, supply current, input power, and output power shall not exceed  $P_D$  at a package base temperature of 70°C
- 3/ Junction operating temperature will directly affect the device median lifetime. For maximum life, it is recommended that channel temperatures be maintained at the lowest possible levels.

**TABLE II**  
**RECOMMENDED OPERATING CONDITIONS**

| Symbol   | Parameter                    | Value           |
|----------|------------------------------|-----------------|
| Vd       | Drain Voltage                | 7.5 V           |
| Id       | Drain Current                | 650 mA          |
| Id_Drive | Drain Current under RF Drive | 1200 mA         |
| Vg3, Vg4 | Gate Voltage                 | -0.65 V typical |

**TABLE III**  
**RF CHARACTERIZATION TABLE**  
( $T_A = 25^\circ\text{C}$ , Nominal)  
( $V_d = 7.5\text{V}$ ,  $I_{dq} = 650\text{mA} \pm 5\%$ )

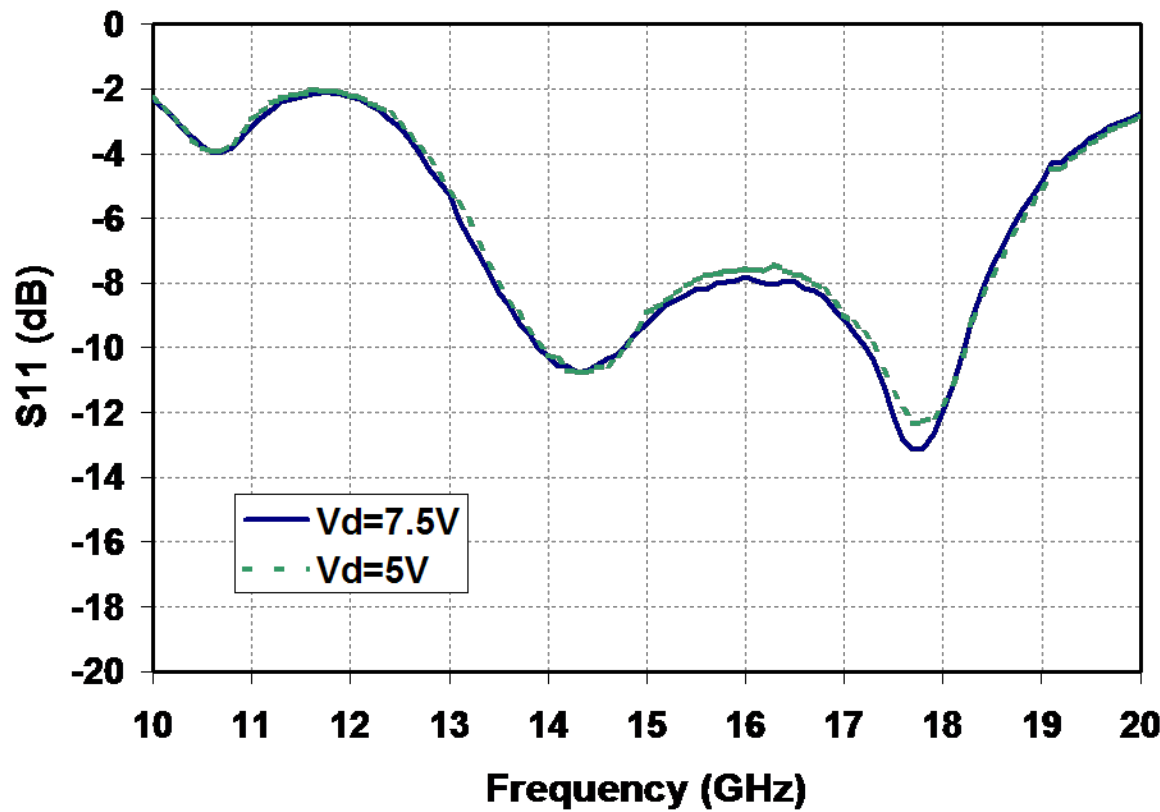
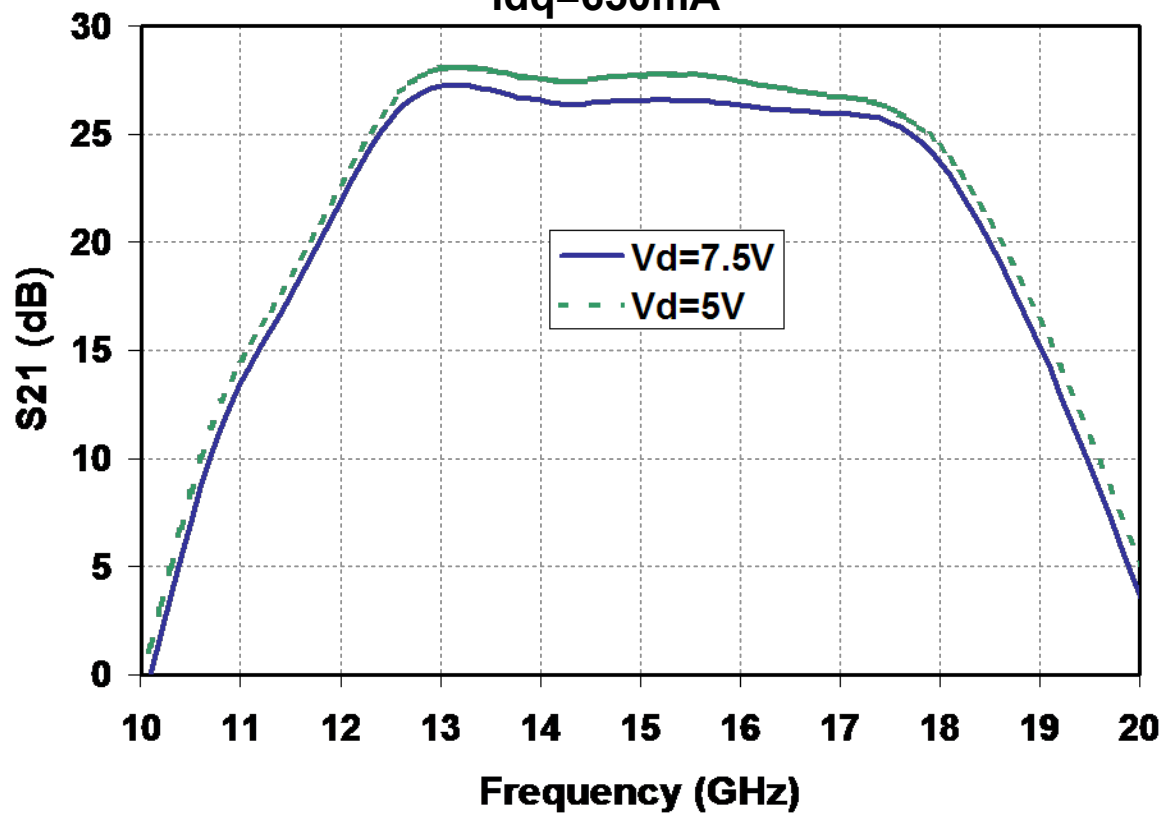
| Symbol | Parameter                                               | Test Conditions             | Typ  | Units | Notes |
|--------|---------------------------------------------------------|-----------------------------|------|-------|-------|
| Gain   | Small Signal Gain                                       | $F = 12.5 - 17 \text{ GHz}$ | 26   | dB    |       |
| IRL    | Input Return Loss                                       | $F = 12.5 - 17 \text{ GHz}$ | 7    | dB    |       |
| ORL    | Output Return Loss                                      | $F = 12.5 - 17 \text{ GHz}$ | 12   | dB    |       |
| PWR    | Output Power @<br>$P_{in} = +15\text{dBm}$              | $F = 12.5 - 17 \text{ GHz}$ | 34.0 | dBm   |       |
| PAE    | Power Added<br>Efficiency @<br>$P_{in} = +15\text{dBm}$ | $F = 12.5 - 17 \text{ GHz}$ | 31   | %     |       |

**TABLE IV**  
**THERMAL INFORMATION**

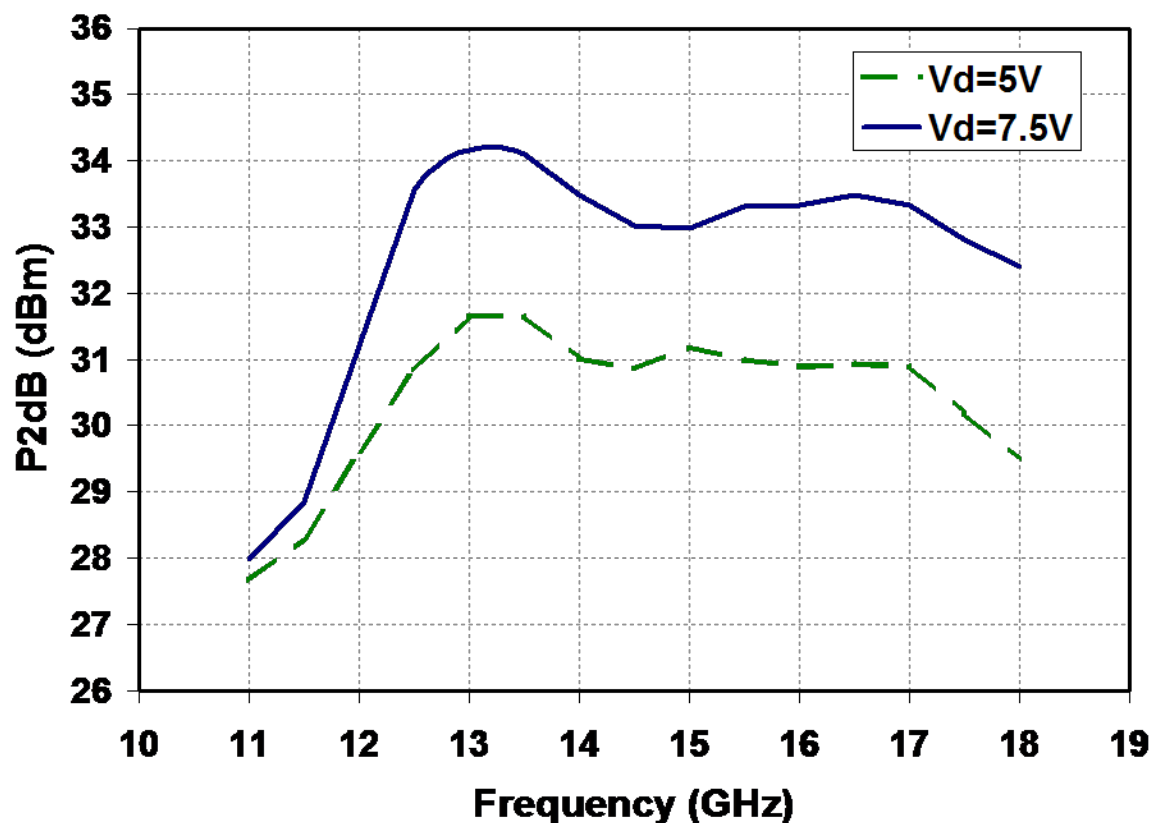
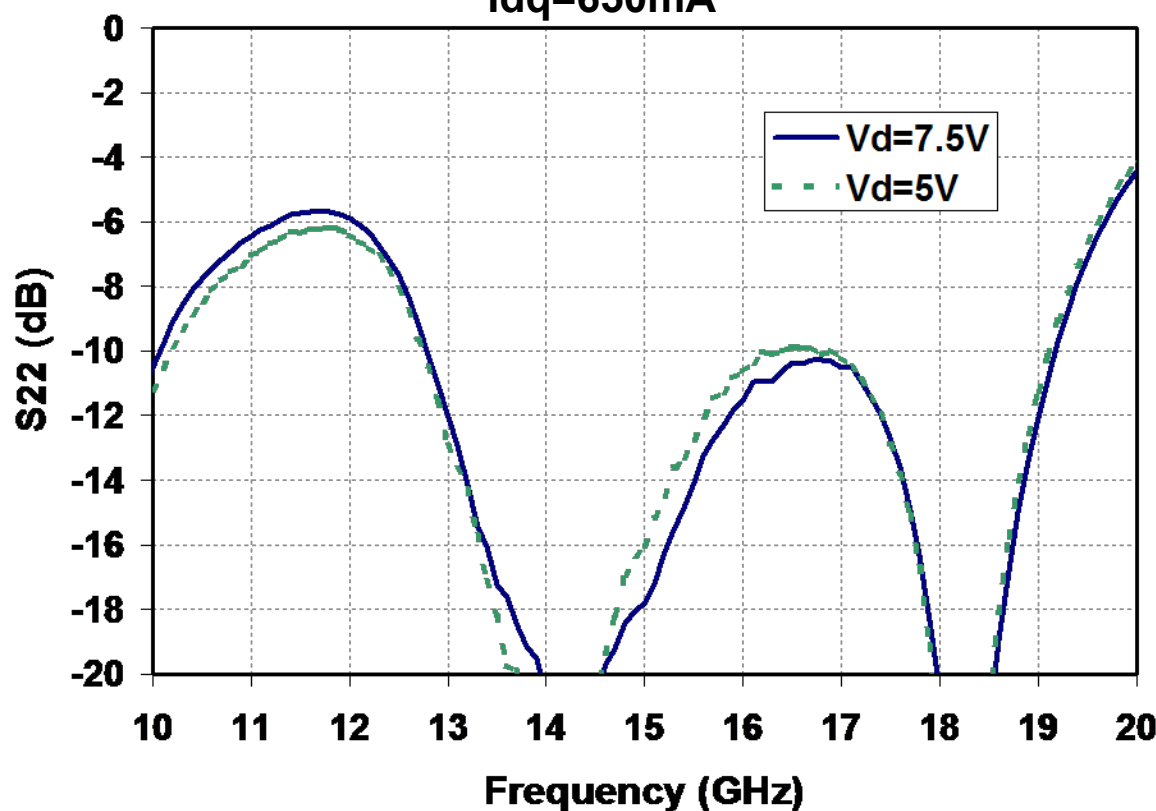
| Parameter                                                               | Test Conditions                                                                                           | $T_{CH}$<br>( $^\circ\text{C}$ ) | $\theta_{jc}$<br>( $^\circ\text{C/W}$ ) | $T_m$<br>(hrs) |
|-------------------------------------------------------------------------|-----------------------------------------------------------------------------------------------------------|----------------------------------|-----------------------------------------|----------------|
| $\theta_{jc}$ Thermal Resistance<br>(Channel to Backside of<br>Carrier) | $V_D = 7.5\text{V}$<br>$I_D = 650\text{mA}$<br>$P_{DISS} = 4.88\text{W}$<br>$T_{BASE} = 70^\circ\text{C}$ | 130.7                            | 12.44                                   | 5.5E+6         |

Note: Assumes eutectic attach using 1.5mil 80/20 AuSn mounted to a 20mil CuMo carrier at  $70^\circ\text{C}$  baseplate temperature. Worst case conditions with no RF applied, 100% of DC power is dissipated.

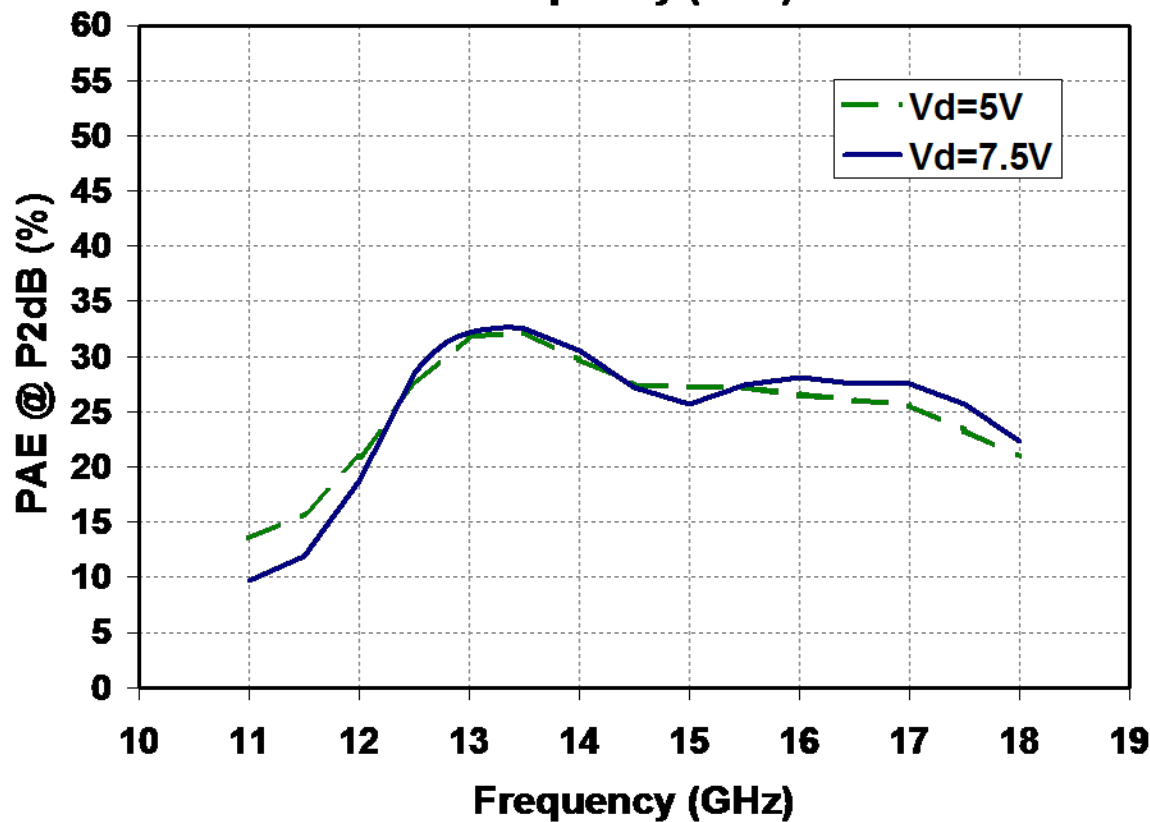
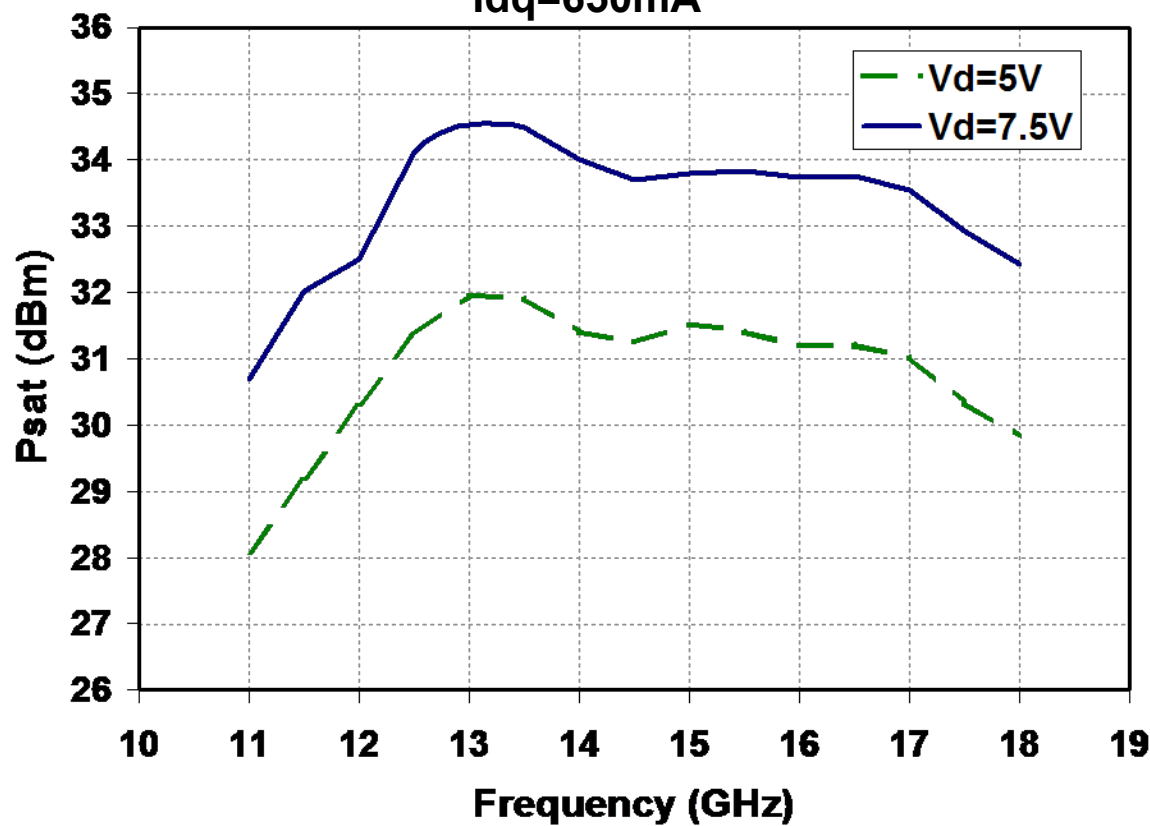
Typical Fixtured Performance  
 $I_{dq}=650\text{mA}$



Typical Fixtured Performance  
Idq=650mA

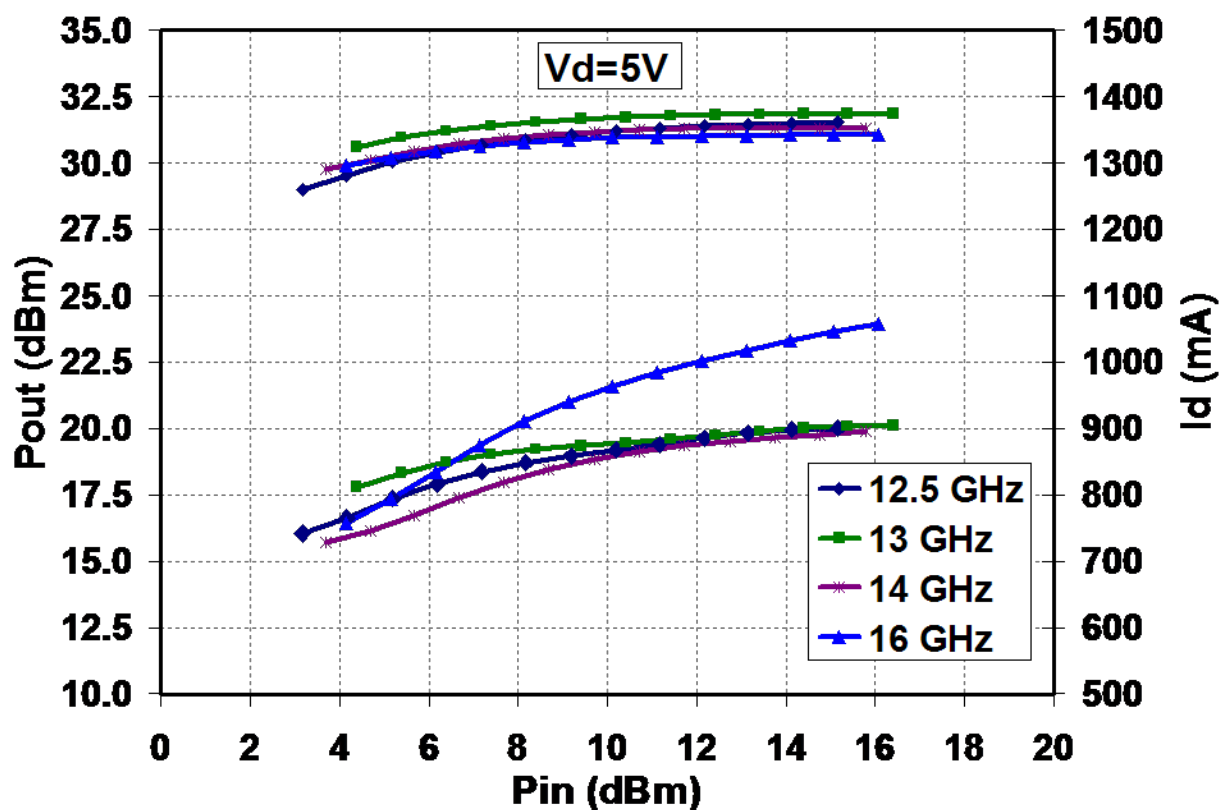
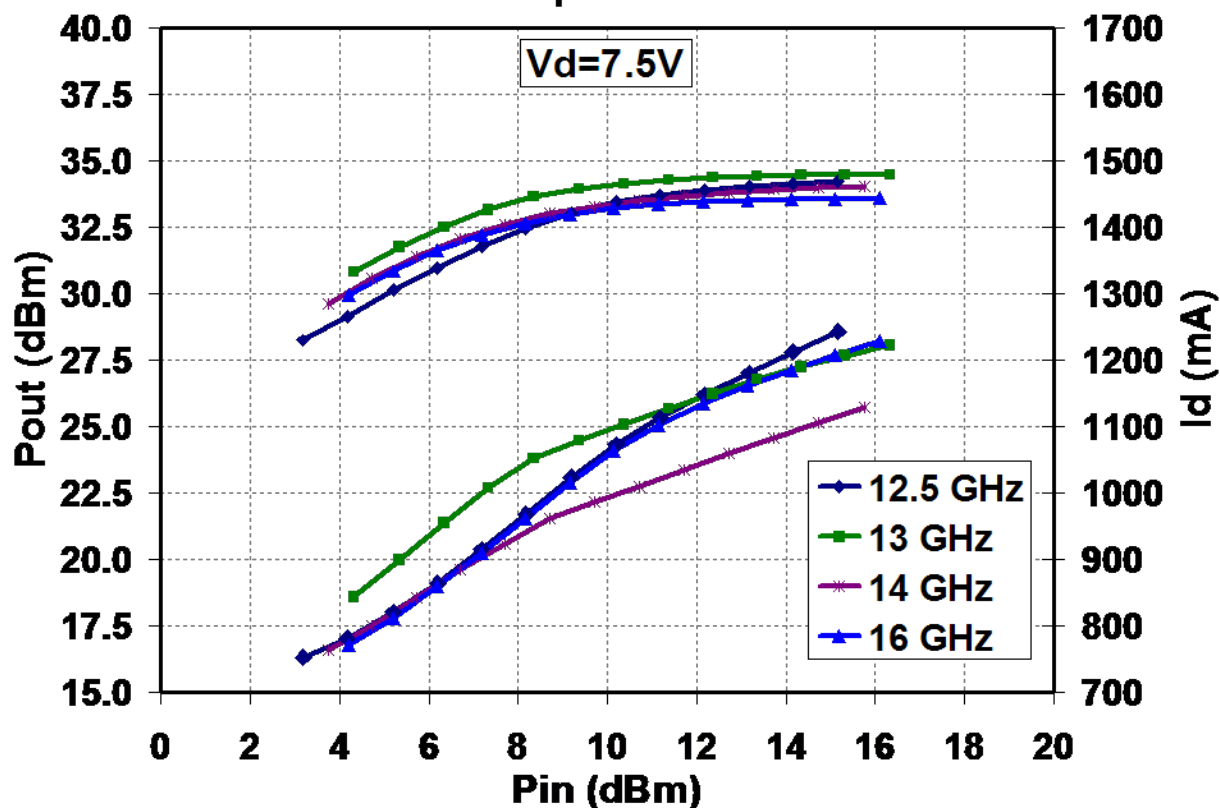


Typical Fixtured Performance  
Idq=650mA



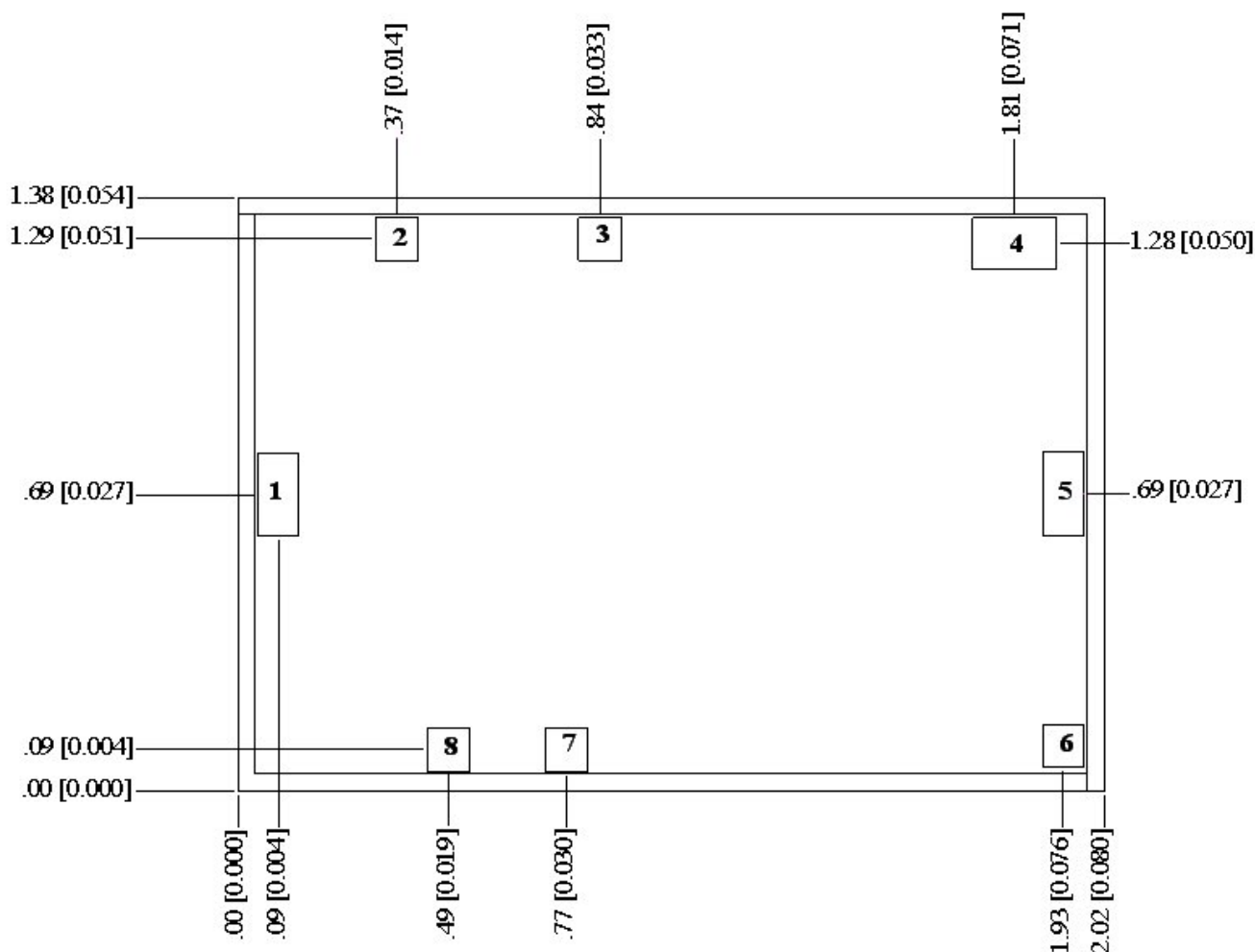
# Typical Fixtured Performance

$I_{dQ}=650\text{mA}$



# Mechanical Drawing

**TGA2510**



Units: millimeters [inches]

Thickness: 0.10 [0.004] (reference only)

Chip edge to bond pad dimensions are shown to center of bond pads.

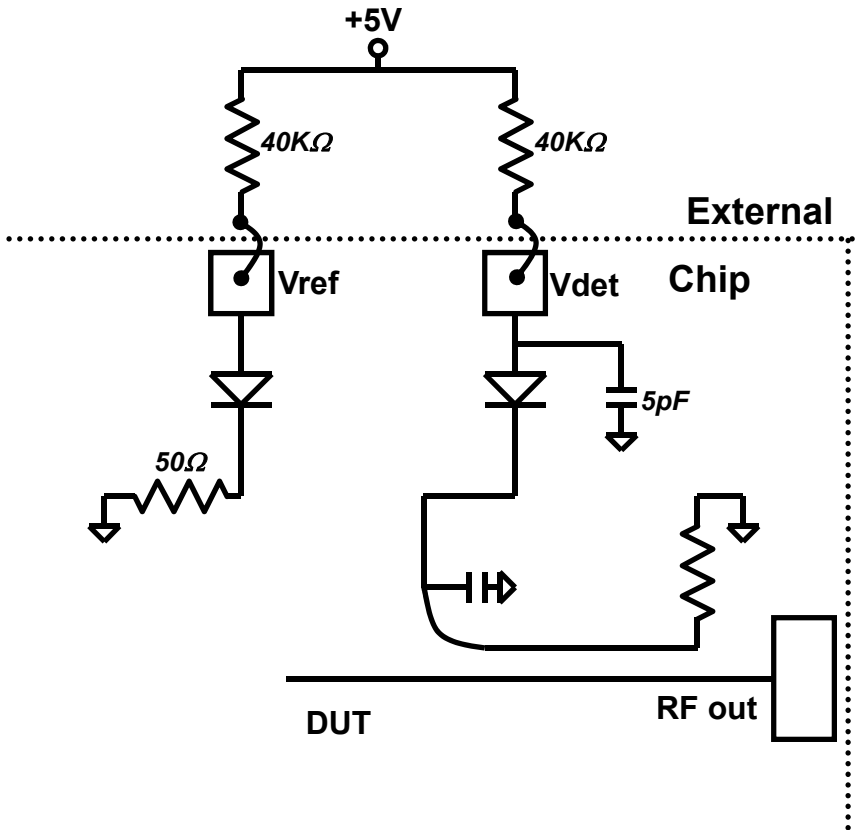
Chip size tolerance:  $\pm 0.05$  [0.002]

RF ground through backside

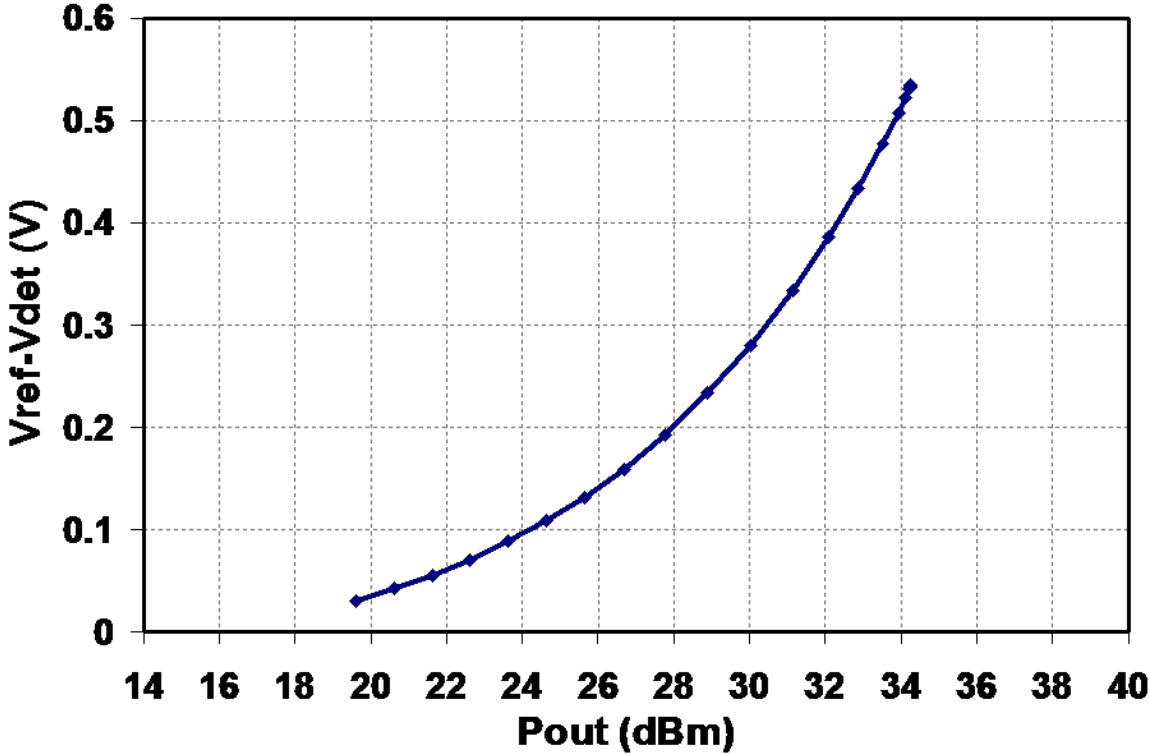
|             |           |             |                 |
|-------------|-----------|-------------|-----------------|
| Bond Pad #1 | RF Input  | 0.10 x 0.20 | [0.004 x 0.008] |
| Bond Pad #2 | Vref      | 0.10 x 0.10 | [0.004 x 0.004] |
| Bond Pad #3 | Vd3       | 0.10 x 0.20 | [0.004 x 0.008] |
| Bond Pad #4 | Vd4       | 0.20 x 0.13 | [0.008 x 0.005] |
| Bond Pad #5 | RF Output | 0.10 x 0.20 | [0.004 x 0.008] |
| Bond Pad #6 | Vdet      | 0.10 x 0.10 | [0.004 x 0.004] |
| Bond Pad #7 | Vg4       | 0.10 x 0.10 | [0.004 x 0.004] |
| Bond Pad #8 | Vg3       | 0.10 x 0.10 | [0.004 x 0.004] |



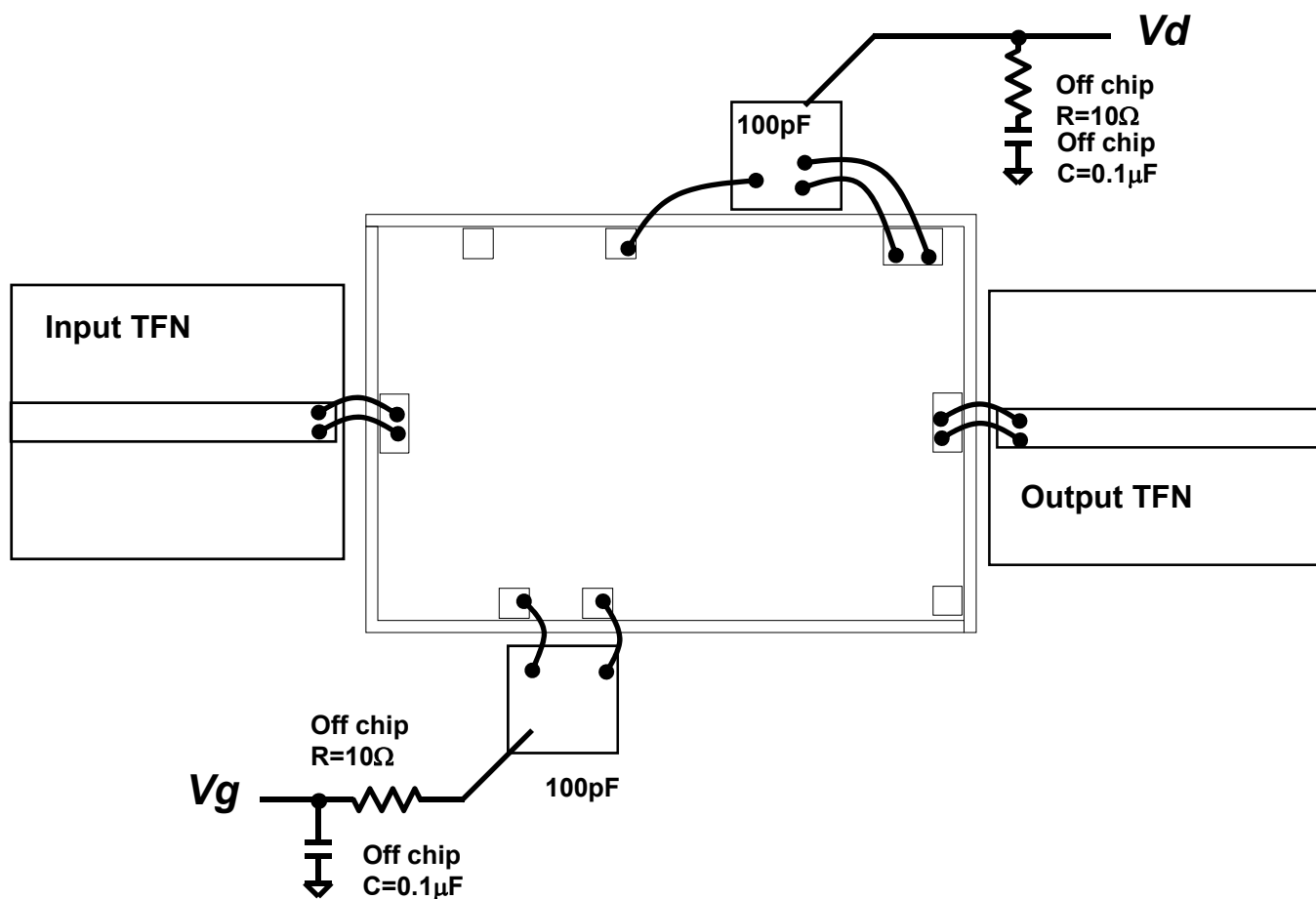
Power Detector



TGA2510 Power Detector @ 14GHz



## Chip Assembly & Bonding Diagram



*GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.*

## **Assembly Process Notes**

Reflow process assembly notes:

- Use AuSn (80/20) solder with limited exposure to temperatures at or above 300°C. (30 seconds maximum)
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- No fluxes should be utilized.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.
- Microwave or radiant curing should not be used because of differential heating.
- Coefficient of thermal expansion matching is critical.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonics are critical parameters.
- Aluminum wire should not be used.
- Maximum stage temperature is 200°C.

***GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.***

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